From the Editor

MegaBooth



The Microscopy & Microanalysis (M&M) meeting is known as the largest annual microscopy meeting with the largest annual exhibition of microscopy instruments and supplies. One regular feature of the exhibition is the Microscopy Society of America's own booth called the MegaBooth, which is visible from the far reaches of the hall because of the huge circular banner above it. This large booth, planned and implemented by volunteers, acts as a central meeting place for many MSA activities at the meeting.

The MegaBooth contains exhibition space for the technologist Certification Program, the Placement Office, Technologists' Forum, Educational Outreach, MSA Publications, a Book Exhibit, and a Membership Booth. It is also the place to get questions answered about the meeting and about the Microscopy Society of America. Of course, the place to read your email and connect to WiFi is the Internet Café, adjacent to the MegaBooth.

The above offices and committees of MSA provide services to members and outreach to microscopists and would-be microscopists. The Certification Program administers examinations to certify biological transmission electron microscopy technologists. The Placement Office is a forum to bring prospective employers together with members seeking employment, and space is provided in the booth to post notices of positions available and resumes of members looking for jobs. The Technologists' Forum is a recognized MSA Committee that promotes all aspects of microscopy of interest to technologists. Educational Outreach is MSA's program to encourage the use of microscopy as a way to interest K through 12 students in science. The MSA publications booth displays back issues of Microscopy and Microanalysis and Microscopy Today. The book exhibit contains many standard reference books and textbooks of interest to microscopists. The membership booth is available to help microscopists learn the benefits of membership in MSA; it also provides information to corporate members on the advantages of becoming a sustaining member. In addition, there are always one or two members of the MSA Council available at the Megabooth to answer questions about the business and governance of the society or about how to become more involved as a volunteer.

If you haven't visited the MegaBooth recently, be sure to stop by at the M&M meeting in Indianapolis this August. Remember ... meet me at the MegaBooth!

Editor-in-Chief Charles Lyman

Publication Objective: to provide information of interest to microscopists.

Microscopy Today is a controlled-circulation trade magazine owned by the Microscopy Society of America that is published six times a year in the odd months. Editorial coverage spans all microscopy techniques including light microscopy, scanning probe microscopy, electron microscopy, ion-beam techniques, and the wide range of microanalytical methods. Readers and authors come from both the life sciences and the physical sciences. The typical length of an article is about 2,000 words plus figures and tables; feature articles are longer. Interested authors should consult "Instructions for Contributors" on the *Microscopy Today* website: www.microscopy-today.com.

ISSN 1551-9295

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Magazine website:

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Publisher

Cambridge University Press 32 Avenue of the Americas New York, NY 10013-2473 (212) 337-5000

Circulation: 18,000

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